

**Notice of References Cited**

Application/Control No.

10/567,701

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

JAE Y. LEE

Art Unit

2466

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,915,325	07-2005	Lee et al.	709/202
*	B	US-6,845,100	01-2005	Rinne, Mika	370/395.43
*	C	US-6,466,985	10-2002	Goyal et al.	709/238
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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